



**COUNCIL OF  
THE EUROPEAN UNION**

**Brussels, 19 March 2014  
(OR. en)**

**7904/14  
ADD 1**

**ENV 292  
MI 286  
DELECT 88**

**COVER NOTE**

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From:	Secretary-General of the European Commission, signed by Mr Jordi AYET PUIGARNAU, Director
date of receipt:	14 March 2014
To:	Mr Uwe CORSEPIUS, Secretary-General of the Council of the European Union
No. Cion doc.:	C(2014) 1641 final - Annex 1
Subject:	Annex to the Commission Delegated Directive amending, for the purposes of adapting to technical progress, Annex IV to Directive 2011/65/EU of the European Parliament and of the Council as regards an exemption for lead in micro-channel plates (MCPs)

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Delegations will find attached document C(2014) 1641 final - Annex 1.

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Encl.: C(2014) 1641 final - Annex 1



EUROPEAN  
COMMISSION

Brussels, 13.3.2014  
C(2014) 1641 final

ANNEX 1

**ANNEX**

**to the**

**Commission Delegated Directive**

**amending, for the purposes of adapting to technical progress, Annex IV to Directive 2011/65/EU of the European Parliament and of the Council as regards an exemption for lead in micro-channel plates (MCPs).**

## ANNEX

to the

### Commission Delegated Directive

**amending, for the purposes of adapting to technical progress, Annex IV to Directive 2011/65/EU of the European Parliament and of the Council as regards an exemption for lead in micro-channel plates (MCPs).**

In Annex IV to Directive 2011/65/EU the following point 39 is added:

"39. Lead in micro-channel plates (MCPs) used in equipment where at least one of the following properties is present:

(a) a compact size of the detector for electrons or ions, where the space for the detector is limited to a maximum of 3 mm/MCP (detector thickness + space for installation of the MCP), a maximum of 6 mm in total, and an alternative design yielding more space for the detector is scientifically and technically impracticable;

(b) a two-dimensional spatial resolution for detecting electrons or ions, where at least one of the following applies:

- (i) a response time shorter than 25 ns;
- (ii) a sample detection area larger than 149 mm<sup>2</sup>;
- (iii) a multiplication factor larger than  $1.3 \times 10^3$ .

(c) a response time shorter than 5 ns for detecting electrons or ions;

(d) a sample detection area larger than 314 mm<sup>2</sup> for detecting electrons or ions;

(e) a multiplication factor larger than  $4.0 \times 10^7$ .

The exemption expires on the following dates:

- (a) 21 July 2021 for medical devices and monitoring and control instruments;
- (b) 21 July 2023 for in-vitro diagnostic medical devices;
- (c) 21 July 2024 for industrial monitoring and control instruments".